



We make it visible.

### **Automated Correlative Tomography using X-ray Microscopy and FIB-SEM**

X-ray microscopy (XRM) provides non-destructive 3D imaging capabilities on specimens across a range of length scales, observing features with sizes spanning from nanometres to millimetres. Recent developments, inspired by results from dedicated synchrotron instruments, have incorporated a number of X-ray optical elements that have driven resolution and contrast to levels previously unachievable by conventional X-ray computed tomography (CT) instrumentation.

As the ZEISS X-ray microscopy group continue to develop laboratory X-ray microscopes, building on the technology developed from the company's synchrotron heritage, we investigate the emerging breadth of applications coming from this new range of instruments. This includes applications from the recently introduced Diffraction Contrast Tomography module, analogous with EBSD.

We will also discuss the latest innovations in correlative microscopy, with developed workflows between XRM and Crossbeam (FIB SEM).